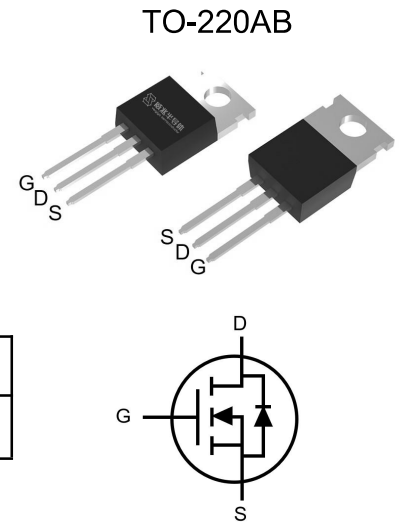


Features

- Enhancement mode
- VitoMOS® II Technology
- Fast Switching and High efficiency
- 100% Avalanche tested, 100% Rg tested



Part ID	Package Type	Marking	Packing
VST012N20HS-G	TO-220AB	012N20H	50pcs/Tube



Maximum ratings, at T_A = 25°C, unless otherwise specified

Symbol	Parameter		Rating	Unit
V(BR)DSS	Drain-Source breakdown voltage		200	V
VGS	Gate-Source voltage		±20	V
IS	Diode continuous forward current	T _C = 25°C	150	A
ID	Continuous drain current @VGS=10V (Silicon limited)	T _C = 25°C	150	A
ID	Continuous drain current @VGS=10V (Silicon limited)	T _C = 100°C	106	A
IDM	Pulse drain current tested ①	T _C = 25°C	400	A
IDSM	Continuous drain current @VGS=10V	T _A = 25°C	8	A
		T _A = 70°C	6	A
EAS	Avalanche energy, single pulsed ②		1296	mJ
PD	Maximum power dissipation ③	T _C = 25°C	750	W
PDSM	Maximum power dissipation ④	T _A = 25°C	2.1	W
TSTG,TJ	Storage and Junction Temperature Range		-55 to 175	°C

Thermal Characteristics

Symbol	Parameter	Typical	Max	Unit
RθJC	Thermal Resistance, Junction-to-Case ⑤	0.17	0.2	°C/W
RθJA	Thermal Resistance, Junction-to-Ambient ⑥	50	60	°C/W

Electrical Characteristics

Symbol	Parameter	Condition	Min.	Typ.	Max.	Unit
Static Electrical Characteristics @ T _j =25°C (unless otherwise stated)						
V(BR)DSS	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	200	—	--	V
I _{DSS}	Zero Gate Voltage Drain Current(T _j =25°C)	V _{DS} =200V,V _{GS} =0V	—	—	1	μA
	Zero Gate Voltage Drain Current(T _j =125°C)⑦	V _{DS} =200V,V _{GS} =0V	—	—	100	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V,V _{DS} =0V	—	—	±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} ,I _D =250μA	2.6	3.1	3.6	V
R _{DS(on)}	Drain-Source On-State Resistance ⑧	V _{GS} =10V, I _D =50A	—	10	13	mΩ
		T _j =100°C ⑦	—	13	—	mΩ
Dynamic Electrical Characteristics @ T _j = 25°C (unless otherwise stated)						
C _{iss}	Input Capacitance ⑦	V _{DS} =100V,V _{GS} =0V, f=1MHz	—	4650	—	pF
C _{oss}	Output Capacitance ⑦		—	410	—	pF
C _{rss}	Reverse Transfer Capacitance ⑦		—	20	—	pF
R _g	Gate Resistance	f=1MHz	—	4.1	--	Ω
Q _g	Total Gate Charge ⑦	V _{DS} =100V,I _D =50A, V _{GS} =10V	—	62	—	nC
Q _{gs}	Gate-Source Charge ⑦		—	22	—	nC
Q _{gd}	Gate-Drain Charge ⑦		—	12	—	nC
Switching Characteristics ⑦						
T _{d(on)}	Turn-on Delay Time	V _{DD} =100V, I _D =50A, R _G =3.9Ω, V _{GS} =10V	—	18	—	ns
T _r	Turn-on Rise Time		—	61	--	ns
T _{d(off)}	Turn-Off Delay Time		—	57	--	ns
T _f	Turn-Off Fall Time		—	50	--	ns
Source- Drain Diode Characteristics@ T _j = 25°C (unless otherwise stated)						
V _{SD}	Forward on voltage	I _{SD} =50A,V _{GS} =0V	—	0.8	1.2	V
T _{rr}	Reverse Recovery Time ⑦	I _{sd} =50A, V _{GS} =0V	—	133	—	ns
Q _{rr}	Reverse Recovery Charge ⑦	di/dt=100A/μs	—	625	—	nC

NOTE:

- ① Single pulse; pulse width $\leq 100\mu s$.
- ② EAS of 1296mJ is based on starting $T_j = 25^{\circ}\text{C}$, $L = 0.5\text{mH}$, $R_G = 25\Omega$, $I_{AS} = 72A$, $V_{GS} = 10V$; 100% FT tested at $L = 0.5\text{mH}$, $I_{AS} = 36A$.
- ③ The power dissipation P_d is based on $T_j(\text{max})$, using junction-to-case thermal resistance $R_{\theta JC}$.
- ④ The power dissipation P_{dsm} is based on $T_j(\text{max})$, using junction-to-ambient thermal resistance $R_{\theta JA}$.
- ⑤ Thermal resistance from junction to soldering point (on the exposed drain pad). These tests are performed on a cool plate.
- ⑥ These tests are performed with the device mounted on 1 in2 FR-4 board with 2oz. Copper, in a still air environment with $T_A=25^{\circ}\text{C}$.
- ⑦ Guaranteed by design, not subject to production testing.
- ⑧ Pulse width $\leq 380\mu s$; duty cycles $\leq 2\%$.

Typical Characteristics

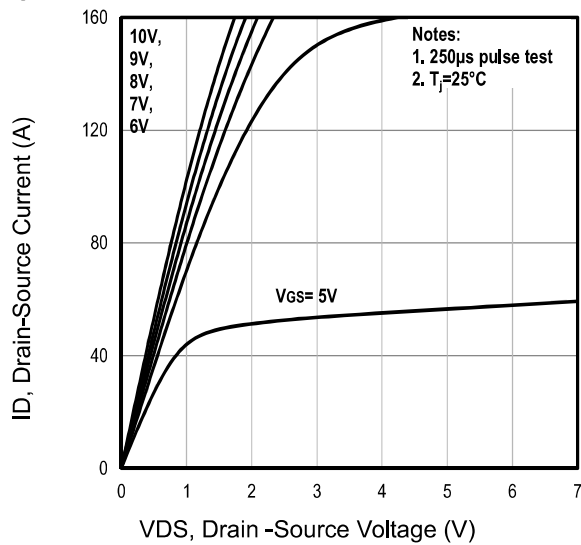


Fig1. Typical Output Characteristics

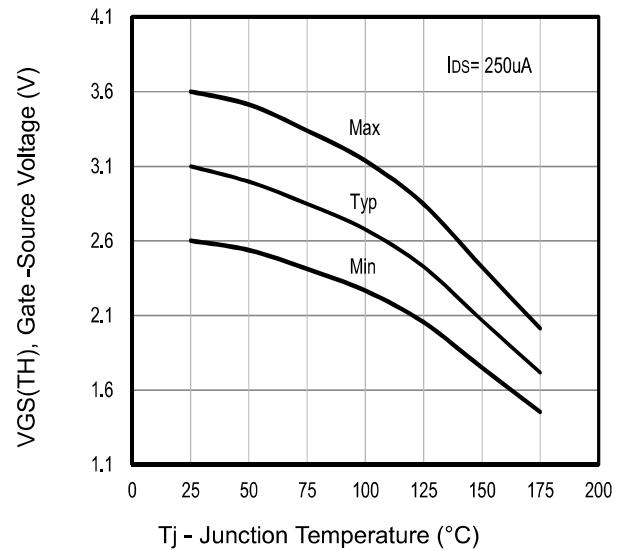


Fig2. Typical $V_{GS(TH)}$ Gate-Source Voltage Vs. T_j

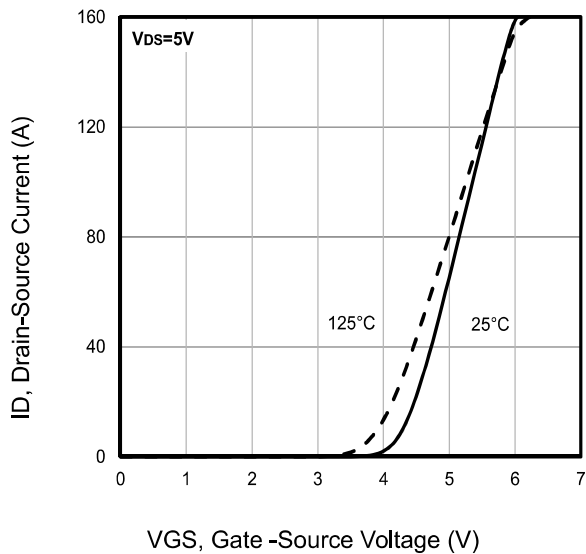


Fig3. Typical Transfer Characteristics

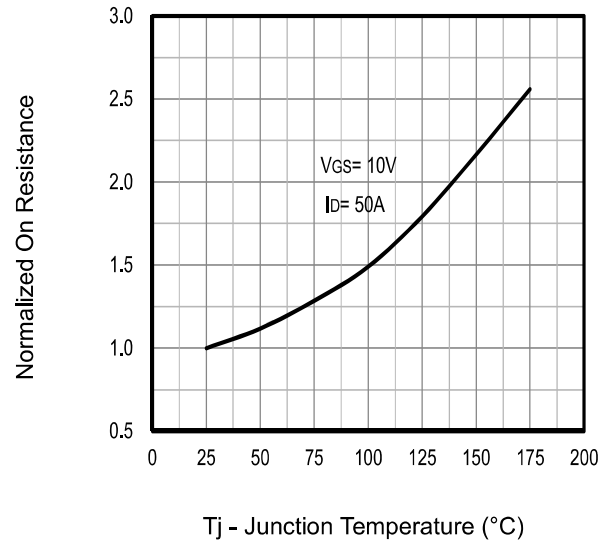


Fig4. Typical Normalized On-Resistance Vs. T_j

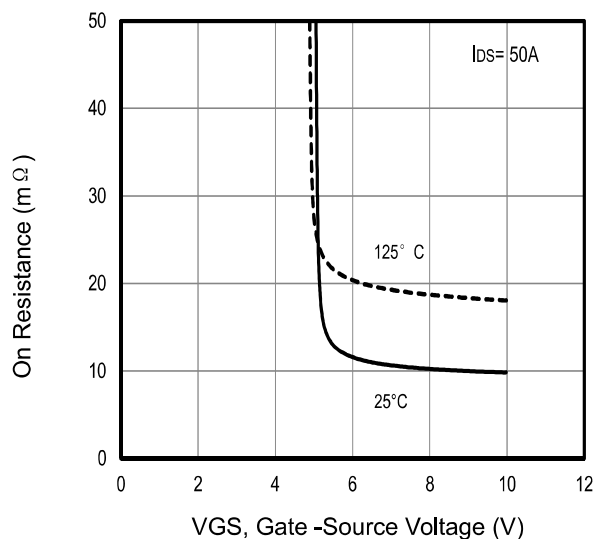


Fig5. Typical On Resistance Vs Gate-Source Voltage

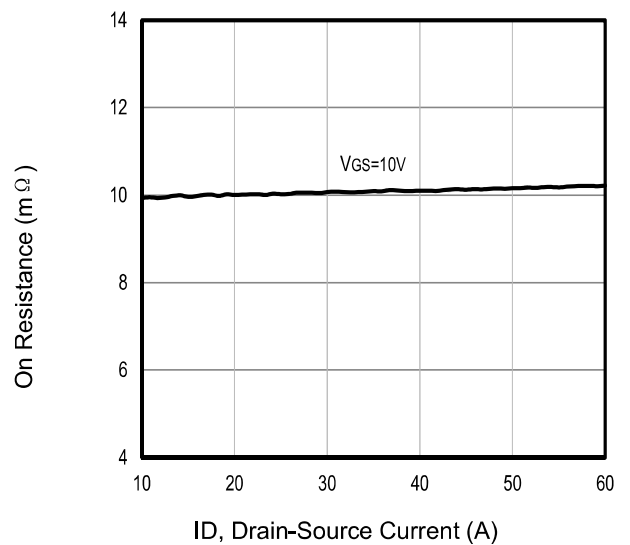


Fig6. Typical On Resistance Vs Drain Current

Typical Characteristics

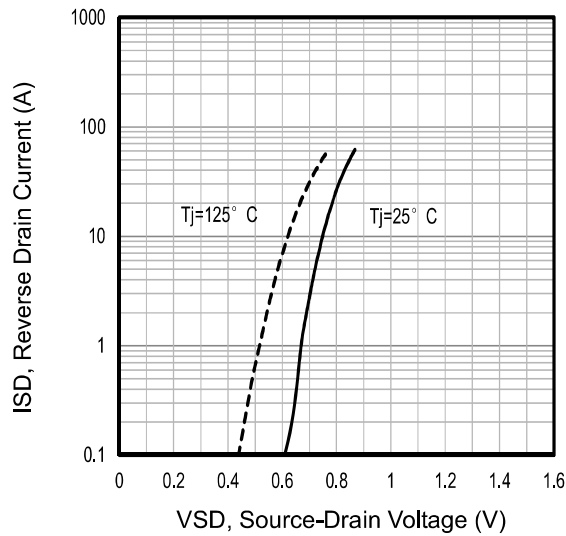


Fig7. Typical Source-Drain Diode Forward Voltage

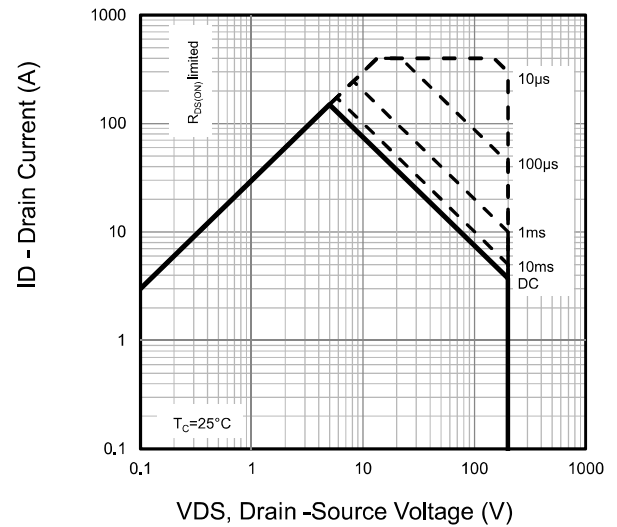


Fig8. Maximum Safe Operating Area

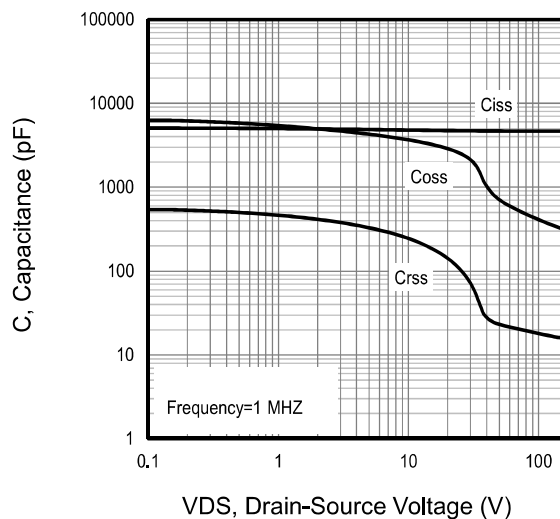


Fig9. Typical Capacitance Vs. Drain-Source Voltage

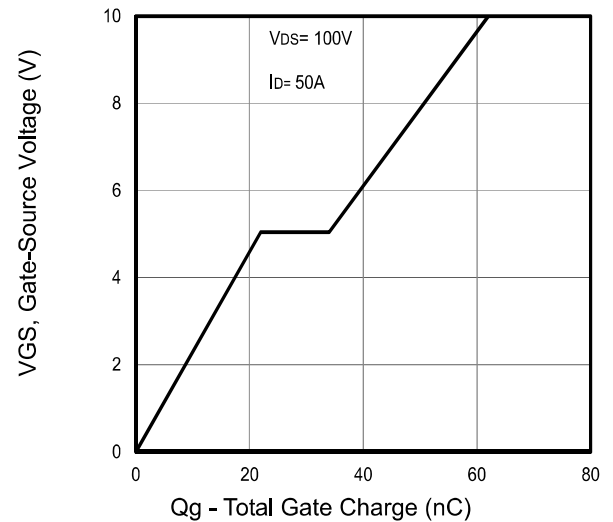


Fig10. Typical Gate Charge Vs. Gate-Source Voltage

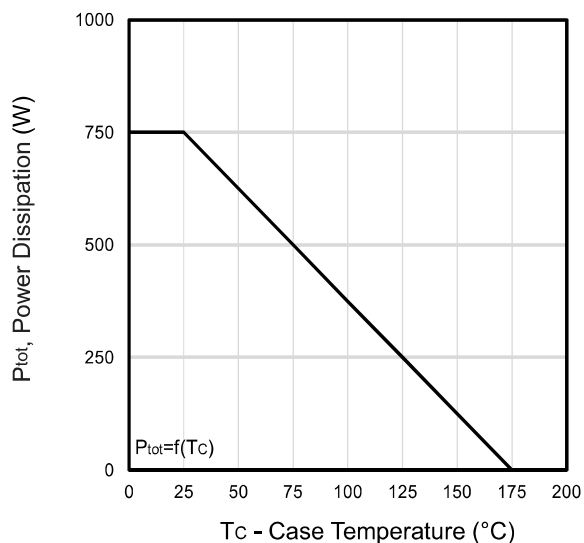


Fig11. Power Dissipation Vs. Case Temperature

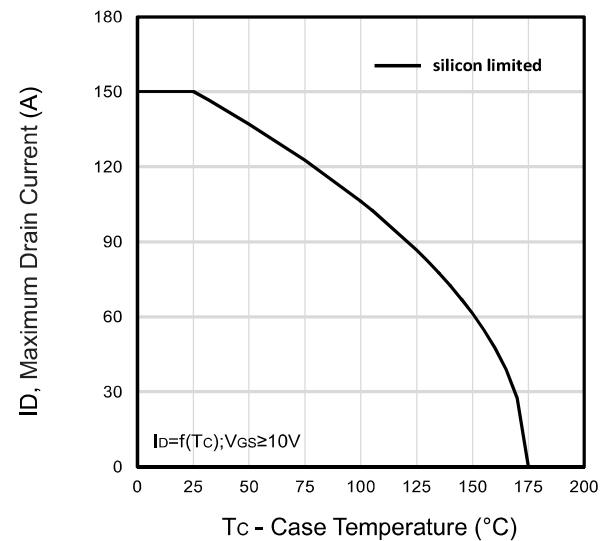


Fig12. Maximum Drain Current Vs. Case Temperature

Typical Characteristics

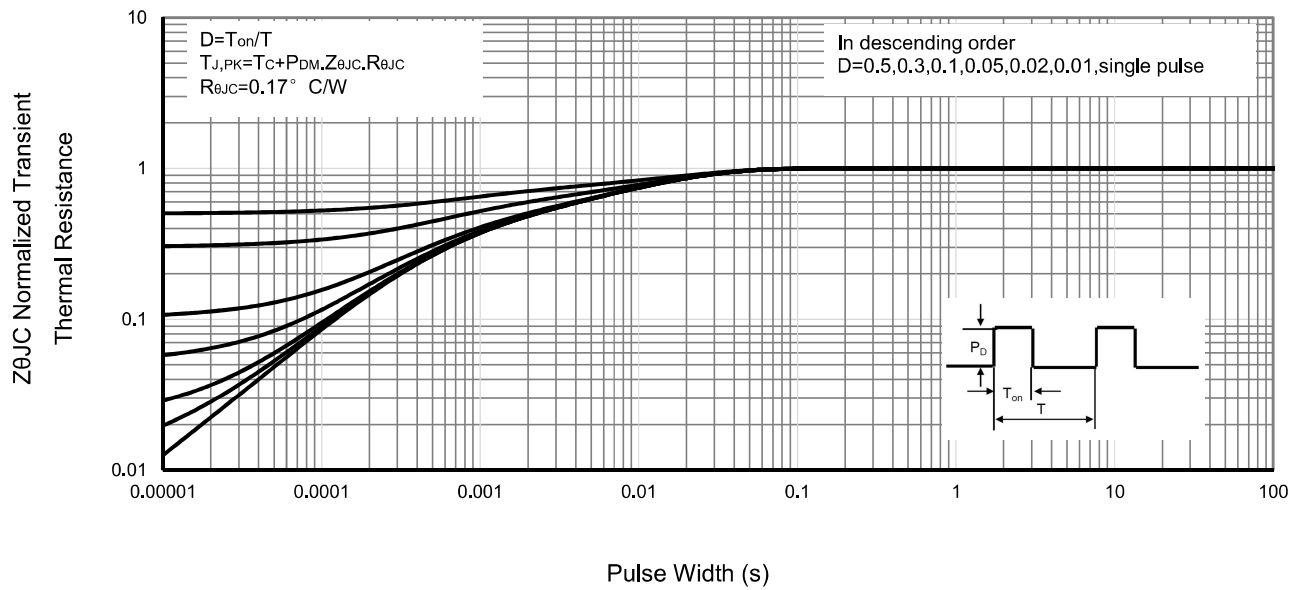


Fig13 . Normalized Maximum Transient Thermal Impedance

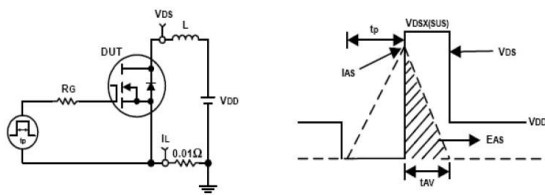


Fig14. Unclamped Inductive Test Circuit and waveforms

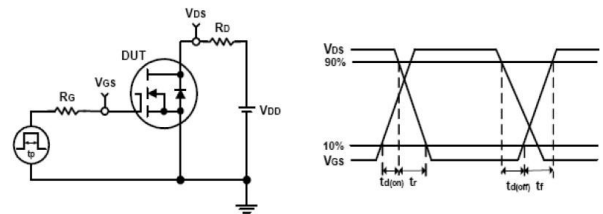
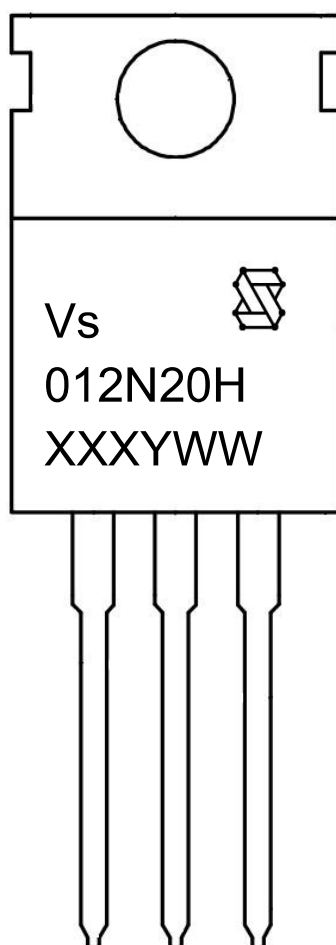


Fig15. Switching Time Test Circuit and waveforms

Marking Information



1st line: Vergiga Code (Vs), Vergiga Logo

2nd line: Part Number (012N20H)

3rd line: Date code (XXXYWW)

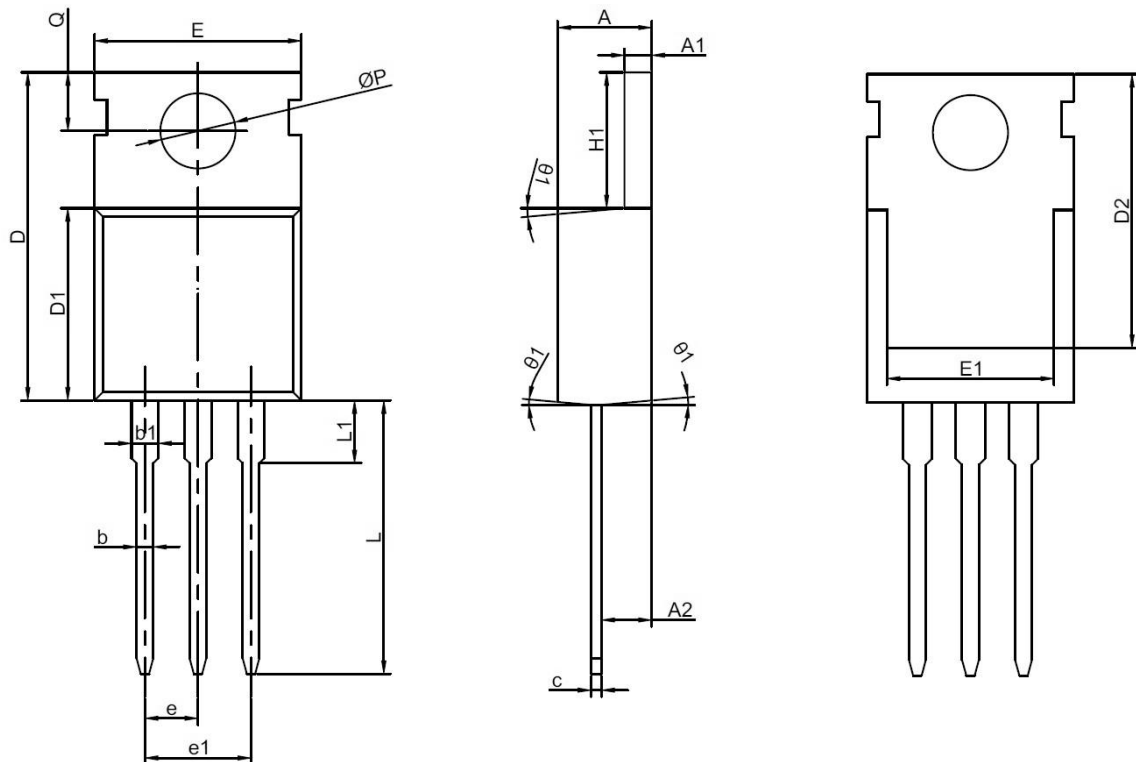
XXX: Wafer Lot Number Code , code changed with Lot Number

Y: Year Code , refer to table below

WW: Week Code (01 to 53)

Code	C	D	E	F	G	H	J	K	L	M	N	P	Q	R	S	T
Year	2015	2016	2017	2018	2019	2020	2021	2022	2023	2024	2025	2026	2027	2028	2029	2030

TO-220AB Package Outline Data



Symbol	Dimensions (unit: mm)		
	Min	Typ	Max
A	4.30	4.52	4.70
A1	1.15	1.30	1.40
A2	2.20	2.40	2.60
b	0.70	0.80	1.00
b1	1.15	1.32	1.50
c	0.45	0.50	0.65
D	15.10	15.70	16.10
D1	8.80	9.20	9.40
D2	12.80	-	13.70
E	9.65	9.90	10.30
E1	7.00	-	8.2
e	2.54 BSC		
e1	5.08 BSC		
H1	6.20	6.50	6.90
L	12.70	-	13.90
L1	-	-	3.50
ØP	3.40	3.60	3.80
Q	2.60	2.80	3.00
θ1	1 °	3 °	7 °

Notes:

1. Refer to JEDEC TO-220 variation AB
2. Dimension "D" and "E" do NOT include mold flash.
Mold flash shall not exceed 0.127mm per side.

Customer Service

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